

10/23/2014



**RELIABILITY MONITOR REPORT
FOR**

San Antonio 0.5 μ m Silicon Gate (E35)

MAXIM INTEGRATED

**160 RIO ROBLES
SAN JOSE, CA 95134**

**This Report was prepared by
MAXIM INTEGRATED Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

DS1088E	DS1629	MAX5128ELA+T
---------	--------	--------------

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 5067 QUANTITY: 205 FAILS: 0 FITS: 22.5

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 10/1/2013 and 9/30/2014 .

Process Information:

Process Description: San Antonio 0.5µm Silicon Gate (E35)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1334	DS1088E	125C, 3.6 VOLTS	192 HRS	77	0	ZJ489578CD-NPI
HIGH TEMP OP LIFE	1341	DS1629	125C, 5.5 VOLTS	192 HRS	80	0	ZJ489579BB-NPI
HIGH TEMP OP LIFE	1417	MAX5128ELA+T	135°C	192 HRS	48	0	TAKQ8A025CB
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1417	MAX5128ELA+T	150°C	500 HRS	80	0	TAKQ8A025CB
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1417	MAX5128ELA+T	-65C TO +150C (Condition C)	1000 CYS	78	0	TAKQ8A025CB
Total:						0	

FAILURE RATE: MTTF (YRS): 5067 QUANTITY: 205 FAILS: 0 FITS: 22.5